# IEC 62754

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# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

colour
inside

## Computation of waveform parameter uncertainties

## Calcul des incertitudes des paramètres des formes d'onde

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| FDIS | Report on voting |
|---|---|
| 85/585/FDIS | 85/X588/RVD |

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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The terms used throughout this document which have been defined in Clause 3 are in italic type.

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# COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES

## 1 Scope

This document specifies methods for the computation of the temporal and amplitude parameters and their associated uncertainty for step-like and impulse-like waveforms. This document is applicable to any and all industries that generate, transmit, detect, receive, measure, and/or analyse these types of pulses.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60469:2013, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*

## 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

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### 3.1
### aberration region

### 3.1.1
### post-transition aberration region

*interval* between a user-specified *instant* and a fixed *instant*, where the fixed *instant* is the first sampling *instant* succeeding the 50 % *reference level instant* for which the corresponding *waveform* value is within the *state boundaries* of the *state* succeeding the 50 % *reference level instant*

[SOURCE: IEC 60469:2013, 3.2.1.1, modified – the note 1 to entry has been deleted.]

### 3.1.2
### pre-transition aberration region

*interval* between a user-specified *instant* and a fixed *instant*, where the fixed *instant* is the first sampling *instant* preceding the 50 % *reference level instant* for which the corresponding *waveform* value is within the *state boundaries* of the *state* preceding the 50 % *reference level instant*

[SOURCE: IEC 60469:2013, 3.2.1.2, modified – the note 1 to entry has been deleted.]